

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the application of:

Yuichi MATSUI

Appln. No.:

Filed: Herewith

For: SEMICONDUCTOR DEVICE AND MANUFACTURING METHOD THEREOF

* * *

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 C.F.R. § 1.56, and without any
assertion as to materiality or prior art effect, the
documents listed on the attached Form PTO-1449 are hereby
cited.

Documents AJ-AO and BJ-BN on the attached List are
cited in the specification, on pages 2-3, and their
relevance is indicated therein.

Respectfully submitted,

NHS:lmb

Miles & Stockbridge P.C.
1751 Pinnacle Drive, Suite 500
McLean, Virginia 22102
(703) 903-9000

By: Nelson H. Shapiro
Nelson H. Shapiro
Reg. No. 17,095

April 22, 2004

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|--|----|--|-------------|-------------------------------------|--------------|-------------------|--------------------|
| FORM PTO-1449 | | | | Atty. Docket No. XA-10070 | | Appln. No. | |
| LIST OF DOCUMENTS CITED BY APPLICANT | | | | Applicant Yuichi MATSUI | | | |
| | | | | Filing Date HEREWITH | | Group | |
| U.S. PATENT DOCUMENTS | | | | | | | |
| Examiner Initial | | Document Number | Date | Name | Class | Sub-class | Filing Date |
| | AA | 5,622,888 | 4/22/97 | Sekine et al. | 438 | 398 | |
| | AB | 6,235,572 | 5/22/01 | Kunitomo et al. | 438 | 240 | |
| | AC | 6,243,255 | 6/5/01 | Kuge et al. | 361 | 528 | |
| | AD | 2003/0011022 | 1/16/03 | Manabe | 257 | 314 | |
| | AE | 6,576,928 | 6/10/03 | Hiratani et al. | 257 | 68 | |
| | AF | 6,673,461 | 1/6/04 | Chazono et al. | 428 | 469 | |
| | AG | 5,970,337 | 10/19/99 | Nishioka | 438 | 240 | |
| | AH | 2003-0151083 | 8/14/03 | Matsui et al. | 257 | 310 | |
| | AI | | | | | | |
| FOREIGN PATENT DOCUMENTS | | | | | | | |
| Examiner Initial | | Document Number | Date | Country | Class | Sub-class | Translation |
| | AJ | 8-139288 | 5/31/96 | JAPAN | | | abstract |
| | AK | 2000-12796 | 1/14/00 | JAPAN | | | abstract |
| | AL | 2000-82639 | 3/21/00 | JAPAN | | | abstract |
| | AM | 2002-164516 | 6/7/02 | JAPAN | | | abstract |
| | AN | 2003-243534 | 8/29/03 | JAPAN | | | abstract |
| | AO | 2001-77108 | 3/23/01 | JAPAN | | | abstract |
| OTHER (including author, title, date, pertinent pages, etc.) | | | | | | | |
| | AP | Rosenfeld, D. et al., "Structural and morphological characterization of Nb ₂ O ₅ thin films deposited by reactive sputtering", <u>American Vacuum Society</u> , 1994, pp. 135-139. | | | | | |
| | AQ | | | | | | |
| | AR | | | | | | |
| Examiner | | | | Date Considered | | | |
| EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant. | | | | | | | |

FORM PTO-1449

Atty. Docket No.

Appln. No.

XA-10070

LIST OF DOCUMENTS CITED BY APPLICANT

Applicant

Yuichi MATSUI

Filing Date

HEREWITH

Group

U.S. PATENT DOCUMENTS

| Examiner Initial | | Document Number | Date | Name | Class | Sub-class | Filing Date |
|------------------|----|-----------------|------|------|-------|-----------|-------------|
| | BA | | | | | | |
| | BB | | | | | | |
| | BC | | | | | | |
| | BD | | | | | | |
| | BE | | | | | | |
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FOREIGN PATENT DOCUMENTS

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| | BJ | 5-345663 | 12/27/93 | JAPAN | | | abstract |
| | BK | 10-12043 | 1/16/98 | JAPAN | | | abstract |
| | BL | 2001-284158 | 10/12/01 | JAPAN | | | abstract |
| | BM | 8-31951 | 2/2/96 | JAPAN | | | abstract |
| | BN | 11-330415 | 11/30/99 | JAPAN | | | abstract |
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OTHER (including author, title, date, pertinent pages, etc.)

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| | BP | |
| | BQ | |
| | BR | |

Examiner

Date Considered

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.